ABSTRACT
NFC and RFID reader battery-powered applications must have a defined and limited energy consumption budget as well as low cost for a product to be realized. Techniques and strategies have emerged over the years for the card presence detection that attempt to address both concerns.

The intent of this application report is to contribute to these techniques and strategies by offering an advancement expressed by adding a simple circuit and small firmware control logic loop to an existing design, which offers dramatic improvement over previously identified card detection solutions.

Additionally, a brief overview of the pros and cons of the known and common implementations of battery-powered RFID and NFC readers is given, and in-depth details are provided on the innovative technique and approach, developed by Texas Instruments for our customers leveraging both the MSP430 (ultra-low power 16-bit MCU) and the TRF79xxA (family of highly integrated NFC/RFID reader/writer ICs) in their battery-powered NFC/RFID reader applications and designs.

The firmware that is described in this application report can be downloaded from http://www.ti.com/lit/zip/sloa184.

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Designers and developers of low-power NFC or RFID systems usually have a list of key requirements that are driven directly by their target markets or focused end equipment. These requirements might include: access control (corporate or industrial building access), digital door locks, “smart” utility meters (for prepayment, technician access, or firmware upgrades), portable speakers, handheld inventory control, handheld data logging collection or medical diagnostic equipment, and mobile or hand-held ticketing or payment terminals.

All of these end equipment examples have similar key "care-about" such as:

- **Total system cost** must be optimized.
- **Electrical design** – Platform or modular designs are becoming more prevalent, with emphasis on being deployable worldwide – that is, one design that can be used in all countries (like a 13.56MHz system based on the TRF79xxA family of devices).
- **Mechanical design** must be robust, safe, and provide various levels of protection against vandalism.
- **User Friendly and Intuitive** – NFC/RFID systems are not line of sight, but users should never need much training to interact with them, so the design must always lend itself to an easy user experience.
- **Low Power Consumption** is more important than ever, and when implemented as described later in this document, can be a real differentiator and competitive advantage.

## 2 13.56MHz NFC/RFID Development System

The TRF79xxA EVMs (see [Figure 1](#)) are self-contained development platforms that can be used to evaluate and test the performance of either the TRF7960A or TRF7970A RFID/NFC transceiver ICs, custom firmware, customer designed antennas, and potential transponders for a customer defined RFID/NFC application. We used these EVMs to demonstrate the concept and so that others could also independently use them to recreate and correlate the findings or make improvements upon them. This application report is for the system developer.
For this example, we operated the reader in a completely embedded mode, at +3VDC, instead of at +5VDC. This was intentionally done to show that when using a commonly utilized battery supply voltage, excellent performance can be achieved from both a detection distance and current consumption perspective, mainly because of the MSP430 (MCU) and the TRF79xxA combination.

3 Commonly Implemented NFC/RFID Card Presence Detection

Mechanical or Optical – A card slot is equipped with a mechanical switch or break beam detector that, when activated, triggers a read cycle of the NFC/RFID card.

Pro: Very low power, consumers and other users are familiar with this interaction.

Con: Card form factor limitations, not robust (easily broken or rendered unusable).
**Resonator** – The NFC/RFID reader is equipped with an additional resonator, oscillator, or crystal and resonant coil. The MCU enables the signal to be generated as a short burst (20 to 50 µs) and detects the antenna dampening.

**Pro:** Low power, no additional mechanical components required

**Con:** Additional electrical components required:
- Two antennas (RFID and Card Sniffer) or switch (capable of handling 13.56MHz signal at power levels up to +23dBm)
- Second oscillator or crystal with a fast run-in time
- EMC Regulation Compliance (frequency and accuracy)
- Detection Distance

![Resonator Approach Diagram](image)

**Figure 3. Resonator Approach**
Capacitive Proximity Sensor – The NFC/RFID reader antenna also comprises areas used for a capacitive sensor. Capacitive proximity sensors detect “target” objects due to their ability to be electrically charged. Because even non-conductors can hold charges, this means just about any object can be detected with this type of sensor. The reader would send out activation commands for the protocols and types of cards expected each time the sensor detects any change.

Pro: Flexible firmware solution, good detection range can be achieved, can be used with all NFC/RFID card types.

Con: High power consumption, detector is measuring E-Field, NFC/RFID card is using H-Field, which can lead to false triggers and wake-ups, and many additional components are required for implementing.

TRF7960A or TRF7970A Received Signal Strength Indicator (RSSI) – The TRF79xxA family of readers employs dual receivers, each with an RSSI detector, inside the IC. The reader system would normally be in an RSSI detection loop, issuing activation commands (by protocol), and then reading out the latched RSSI value (in the RSSI register). Based on the RSSI value returned, the firmware logic would then either issue additional commands (for that protocol) or remain in RSSI detection loop.

Pro: No additional components needed, flexible firmware solution, good detection range can be achieved, can be used with all NFC/RFID card types.

Con: Higher power consumption and peak current, medium detection resolution (both only as compared to other solutions).
4 Ultra-Low Power (ULP) NFC/RFID Card Presence Detection

4.1 Introduction

The proposed solution combines some of the older ideas with new approaches. Carefully chosen values of the analog circuit components and some MSP430 firmware, which leverages the low power modes and port settings available in the MSP430 itself, with logical loop control of the TRF79xxA power modes are the main differences. Compared to the implementations listed in earlier sections, the technique outlined in this section dramatically lowers the power consumption.

The basic idea of this improvement is to combine part of the resonator concept with the existing NFC/RFID reader system based on the TRF79xxA + MSP430. The existing NFC/RFID Reader system used in this example is the TRF7970AEVM, which has the TRF7970A and the MSP430F2370 or the MSP430G2xx parts that have the MSP430 Comparator A+ module integrated and the ability to accept HF clock in (for synchronization purposes).

4.2 Technical Summary

This card presence detection system senses the card by measuring the decay time of a transmitter signal after it has been turned off. When a card is in the field of the transmitter, power transfer occurs, and with more current the voltage on the transmitter output increases. The closer the card is to the reader the higher the voltage will be from the not present state. Measuring the decay of this signal by a comparator creates a simple A/D, since effectively the voltage is what is being measured. Longer times, until the output signal crosses a lower threshold, indicate higher voltages and shorter times indicate lower voltages.

This system is created by adding and changing a few components from the original TRF7970A EVM and using an internal comparator on the MSP430F2370 that was not used before.

The power savings are quite substantial from always running the transmitter. In a system where there are three polls per second, the system is only active approximately 1% of the time. In the sleep state the TRF79xxA consumes almost no power, while the MSP430 is consuming a negligible amount of current (approximately 0.8 μA). In the active state, which lasts several milliseconds, the TRF7970A is quickly turned on, initialized, and a transmitter burst is performed. This turns on the transmitter for approximately 20 μs. Before it is turned off, the comparator is initialized and a timer is started to measure the time. The timer runs until the comparator issues an interrupt indicating that the threshold voltage has been crossed. The timer time at this point is the decay time of the signal. As mentioned earlier, longer times indicate power coupling, which means that a card may have been in the field.

To determine if a certain time measurement indicates that a card is in the field, it is run through what is referred as "automatic calibration algorithm". To explain this need, let's examine what would happen without it. Without it, a specific time value, that once exceeded, would indicate that a card is in the field. However, due to power supply or temperature drifts, this threshold time would be naturally crossed periodically, causing false positives. False positives are very undesirable in this system as they cause a reading process to happen, which uses a lot of power.

The "automatic calibration algorithm" takes the highest sample that it finds in its history memory buffer and adds THRESHOLD_OFFSET to it. This new value becomes the threshold in determining if the current sample needs a read to be performed.
4.3 Hardware Description

4.3.1 System Overview

Figure 6. ULP Card Presence Detection and NFC/RFID Reader Circuit

Figure 6 shows a high-level overview of the system design. The core of this design is based on the TRF79xxA EVM. Shown here is the complete system. The components in blue indicate which components are extra for the card proximity detector circuit.

4.3.2 Detail Sense Circuit

Figure 7 shows the envelope detector plus the RC low pass filter circuit connected to the CA1 input and a zoomed in view of the MSP430 COMP_A internals. The COMP_A output (CAOUT) is fed to the Timer A module, which is used to measure the CAOUT rising edge timings.

NOTE: With RC feeding CA1 input with zoom on internals of COMP_A

Figure 7. HF Envelope Detector
4.3.3 Detail Internal Comparator Circuit Configuration

MSP430 Comparator A+ Module: The main function of the MSP430 Comparator A+ module is to indicate which of the two voltages it is presented with, \(V_{CA0}\) or \(V_{CA1}\), is higher. The output CAOUT is set accordingly:

If \(V_{CA0} > V_{CA1}\) then: CAOUT = 1, else: CAOUT = 0

The two voltages \(V_{CA0}\) and \(V_{CA1}\) can be external or internal reference voltages. Any combination is possible. (See Figure 8 and SLAA071 for further reference.)

![Comparator A+ Block Diagram](image)

Figure 8. Comparator A+ Block Diagram

Other important attributes of the MSP430 Comparator A+ module are:
- Very low input current at the comparator inputs CA0 and CA1
- Can be switched off to minimize current consumption (control bit CAON)
- Controlled by three memory-mapped control bytes (see Section 1.2 of SLAA071)
- Stability with slow-changing input voltages (control bit CAF) can be provided by switching of an analog filter to the comparator output.
- Interrupt capability for the leading and trailing edges of the output signal CAOUT. Use without interrupt is also possible.
In this ULP Card Presence Detection implementation, the use of the Comparator A+ module is a critical detail. Its integration into the MCU guarantees a reduced BOM count compared to the resonator approach previously presented. Additionally, the MSP430 firmware control allows a wide range of customization and optimization.

If for some reason, use of the Comparator A+ choices of 0.7V, 0.25VCC, or 0.5VCC is not possible, an external voltage divider may be used. However this will likely result in higher power usage as the internal comparator efficiently enables the internal voltage divider and disables it when it is not being used.

**NOTE:** Comparator A+ module is not the only comparator module available in the MSP430 families. Other modules could be used, but most likely would require modification to the firmware that is provided with this application report.

### 4.4 Signal Analysis

**Figure 9. Operational Signals (RF, MOD CONTROL, DEMOD and CAOUT)**

*Figure 9 shows a graphical representation of one cycle of the card presence detection process, where the RF Carrier (RF1) is turned on for a short period. During the transmit ON-time, the RC is charging up quickly, when the transmitter is turned OFF, the capacitor C1 begins to discharge and the DEMOD signal is observed to make the measurement.*

*The circuit was simulated for evaluating and arriving at the correct circuit topology and values needed for the timing and performance desired. This effort can be seen in Figure 10 and Figure 11. We can see that the RC (R1, C1) is charging up to steady state and then fully discharging after the transmit signal is no longer applied.*
The circuit in Figure 6 was constructed on a TRF7970AEVM and firmware was written for the MSP430F2370 (MCU driving the TRF7970A), which is following the general flow outlined in Figure 15. In Figure 11, the red trace represents DEMOD signal that is the feedback coming from the transmitter. That is powered on for a brief time and then it is allowed to decay. Once the transmitter is turned off, the timer is started counting until the CAOUT signal is asserted. The count between the transmitter turning off and CAOUT being asserting is the sample time. The EVM was operated at +3VDC, representing the common voltage level used in battery-powered applications today (for example, one CR2032, or two AAA, or two AA, or two C, or two D style batteries in series).
Figure 12 shows one entire card presence detection. The EN line is asserted, turning on the TRF79xxA. There is a short delay to configure the TRF79xxA and allow it to initialize itself. Then the transmitter is turned on and a sample is performed after it is turned off. The DEMOD line can be seen as it goes high and starts to decay. Then the EN pin is turned off and the device goes into sleep mode until the next active period.
In Figure 13, the pin is asserted, which turns on the transmitter (shown green on channel 3). The sense line (shown red on channel 2) goes high as it monitors the transmitter output. The transmitter is turned off and the sense line starts to decay as the capacitor is being discharged. Eventually the comparator's voltage threshold is crossed (at approximately 1.5V) and the comparator output (CAOUT, shown in purple on channel 4) is changed. This interrupts the MCU and the time from the transmitter off to the CAOUT going high is taken, which becomes the sample time.
Figure 14 shows an active cycle that is determined to have detected a card. After the active cycle is completed, the ISO read cycle is started to read the card.

4.5 System Design Considerations

A common system clock is required. MSP430 must be clocked with SYS_CLK (from TRF79xxA) during the sniff period. This is because the system is very sensitive to any changes. Operating the TRF79xxA and MSP430 asynchronously results in random phase changes between the TRF79xxA's SYS_CLK and the MSP430 clock. These minor time differences are enough to create significant changes in transmitter burst waveform but the worst result is that these changes are random. Having a synchronous system means that the transmitter burst waveform and the sensing mechanism can be repeated almost perfectly. This allows the system to be very sensitive to any changes.

The system can operate from 2.7V to 3.6V. Going higher is not recommended because the analog signal coming from the TRF79xxA transmitter to the comparator input will reach voltages that are not recommended to the GPIO coming into the MSP430.

Any changes in the system voltage level (higher or lower) will affect the TRF79xxA's transmitter voltage. This will also affect the RC decay time measured by the comparator. Since the system is very sensitive, false positives will start to occur. Changes as small as 10mV on the power supply voltage can cause false positives, thus it is important that a regulator be used. However, if it is not possible to have a regulator, automatic calibration will be needed. The current firmware does have this feature. This feature tracks the sample sense time and adjusts the threshold time that will trigger a read. Thus, the power supply voltage level can change gradually and significantly over time and still not cause false positives.
5 Firmware Description

5.1 General Overview Flow Diagram

Figure 15 shows the general main loop flow chart.

![Flow Diagram]

Figure 15. General Overview Flow Diagram
5.2 Firmware Analysis

The following code is the main loop that the program runs through.

```c
// infinite loop
while(1)
{
    // we will power down the TRF7970A into Power Down Mode 0 -
    // (total power down) no clock source will be available to
    // run the MSP430 thus the internal MCU clock DCO is needed
    McuOscSel(DCO_CLOCK_SOURCE);
    // Running at 8 MHz
    // Put the TRF into shutdown mode, very little power consumption.
    // No memory is retained in this state
    TRF_DISABLE;
    // prepare the device for low power state
    SetupSleepState();
    // clock will be ACLK (at 12kHz), 3996 cycles or ~.333 seconds
    SetWakeupTimer(SYSM_SLEEP_TIME, ACLK_CLOCK);
    // Timer B will wake-up the MCU
    __bis_SR_register(LPM3_bits + GIE);
    // reset the port settings for operation
    SetupWakeState();
    // reinitialize the SPI module
    Trf797xReConfig();
    // enable the TRF from low power state into active
    TRF_ENABLE;
    // sleep 50uS
    SetWakeupTimer (400, SMCLK_CLOCK);
    // Timer B will wake-up the device
    __bis_SR_register(LPM0_bits + GIE);
    // Reinitialize the TRF7970A
    SniffInitialSettings();
    // 2.9ms to allow the TRF79xxA to initialize (mainly the crystal)
    SetWakeupTimer (35, ACLK_CLOCK);
    // Timer B will wake-up the device
    __bis_SR_register(LPM3_bits + GIE);
    // Initialization for card sniffing
    InitForCardSniff();
    // give time for the clock change to stabilize
    __delay_cycles(50);
    // set up the system for clock source of the TRF79xxA-
    // running at 13.56MHz
    McuOscSel(TRF_CLOCK_SOURCE);
    // Pulse the transmitter and record the time the signal crosses the
    // threshold voltage
    time = ComparatorSlopeTime();
    if (time == 0)
    {
        // this is the case where a timeout occurred in
        // ComparatorSlopeTime(), return to the start
        continue;
    }
    // this block only executes on startup and not afterwards
    // it is for initial calibration
    if (Initial_Calibration (time))
    {
        continue; //initial calibration is not complete
    }
    // does automatic calibration indicate that a threshold was
    // exceeded and a read should occur?
    if (Automatic_Calibration(time, THRESHOLD_OFFSET))
    {
        //do a card read here
    }
}
5.3 Detailed Firmware Flow Diagram

START

Switch to DCO Clock (Configured to run at 8 MHz)

TRF79x0A is disabled
(EN = 0, EN2 = 0)

Timer_B is configured for SYSTEM_SLEEP_TIME delay before wakeup, MCU enters sleep mode (LPM3)
This delay determines the sampling rate

MCU wakes up and enables the TRF79x0A

Timer_B is configured to wakeup the MCU in about 50µs, MCU enters sleep mode (LPM0)
This delay allows the TRF79x0A to properly initialize

TRF79x0A registers are initialized.
Soft Init (83h), Idle (80h)
Regulator Control Register is set to 00h
Chip Status Control set to 80h (standby state)
Mod Control Register is set to 00h (SYS_CLK Off)

Timer_B is configured for 2.9ms delay before wakeup, MCU enters sleep mode (LPM3)
This delay allows the TRF79x0A to properly initialize

Mod Control Register set to 30h (SYS_CLK 13.56MHz)
ISO Control Register is set to 02h

To next page

Figure 16. Detailed Firmware Flow (Part A)
From previous page

MCU switches clock to SYS_CLK (13.56 MHz)

Comparator A+ and Timer A are initialized

TRF79x0A transmitter is activated for 20µs

Timer A (times the sample time), Timer B (exit in case comparator never interrupts) are started

MCU is in LPM0 mode, waiting for IRQ

Comp_A

Timeout

Return 0

Halts Timer A, Returns TAR value (Timer A count time)

TAR

Does Automatic Calibration Algorithm indicate a read is necessary?

NO

YES

Return to Start

Performs polling cycle for NFC/RFID Cards

Figure 17. Detailed Firmware Flow (Part B)
5.4 Description of User Modifiable Parameters

- **MOVING_WINDOW_WHERE_MAXIMUMSAMPLEISCOMPENSATEDFOR**
  This variable essentially decides what the remembering capability of the algorithm is. How long it will keep a certain value for in memory. Samples that have aged past this value are no longer valid. So for example, setting this parameter to 60 will cause the algorithm to keep the recent sample, if it is significant, for at most the next 60 samples.
  Recommended starting value: 60
  For a sampling rate of three times per second, the memory length of the algorithm is 60/3 or approximately 20 seconds.

- **NUMBER_OF_MAXIMUMVALUESTOTRACK**
  This value determines the actual memory buffer size. It does not have to be the exact size of MOVING_WINDOW_WHERE_MAXIMUMSAMPLEISCOMPENSATEDFOR, because the algorithm does some optimization on how it stores the significant samples that it receives in the buffer. This parameter should be approximately 1/2 of MOVING_WINDOW_WHERE_MAXIMUMSAMPLEISCOMPENSATEDFOR but no less than 3 or 4 times THRESHOLD_OFFSET.
  Recommended starting value: 30

- **THRESHOLD_OFFSET**
  This parameter determines the margin that is between the no-card sample state and detection threshold. If a new sample is equal or greater than no card value plus THRESHOLD_OFFSET, then a read is initiated. If this value is too low, false positives can occur. Too high and detection range will be reduced.
  Recommended starting value: 3

- **DELAY_LINE_NUMBER_OF_SAMPLES**
  This determines the size of the delay line. Samples that come into the delay line are not acted on until they exit the delay line. They exit into the algorithm. The delay is needed so that it can all be set to the oldest value in it immediately once a card read has been detected. This is so that the activity leading up to the card read is not used by the calibration routine so to prevent any corruption of it.
  Recommended starting value: 15
  Using this setting, for a sampling rate of three times per second, the delay line will delay a sample just taken for five seconds.

- **IGNORE_SAMPLESAFTER_READ**
  This determines the number of samples after a read has been performed until the next possible detection or read. This is needed to both save power on repetitive reads, as well as prevent any detection while the card is still in the proximity of the reader and thus influencing the automatic calibration algorithm.
  Recommended starting value: 9
  For a sampling rate of three times per second, the next possible read or detection after a read would be in three seconds.

- **SYSTEM_SLEEP_TIME**
  This parameter times 1/12000 is the time that the system spends in the main sleeping period. The reciprocal of this time is the sample frequency of the system.

- **SAMPLESTODISCARD**
  This parameter determines, in the initial calibration algorithm – not the automatic one, how many initial samples to not use in calibration.

- **CALIBRATE_CYCLES**
  This parameter determines how many cycles are used in the initial calibration.

- **USE_AUTOMATIC_CALIBRATION**
  If defined, automatic calibration is used. If not, uses only the calibration value from the initial calibration. If device drifts, false positives are possible. This is useful for testing detection ranges.
5.5 Automatic Calibration Algorithm

Automatic calibration changes the detection threshold based on the previous values that it has received. The algorithm searches the buffer for the maximum time value, adds THRESHOLD_OFFSET to it, and this becomes the threshold that, if met or exceeded, will determine if a read is performed.

It stores a certain amount of samples in a buffer that ages the samples. The samples that are older than MOVING_WINDOW_WHERE_MAXIMUM_SAMPLE_IS_COMPENSATED_FOR are erased and make way for new sample values. It is important to have a finite recent memory for two reasons. First any corruption of the calibration will be in effect for a finite period of time. Also a limited memory is very much necessary when working on value line devices.

NUMBER_OF_MAXIMUM_VALUES_TO_TRACK sets the actual buffer size.
MOVING_WINDOW_WHERE_MAXIMUM_SAMPLE_IS_COMPENSATED_FOR may be greater than NUMBER_OF_MAXIMUM_VALUES_TO_TRACK. The algorithm is able to optimize which high time values that it stores in the buffer so the buffer size may be less than the "window" that it is tracking. A good rule of thumb is to make NUMBER_OF_MAXIMUM_VALUES_TO_TRACK approximately 1/2 of the size of MOVING_WINDOW_WHERE_MAXIMUM_SAMPLE_IS_COMPENSATED_FOR but at least three or four times the value of THRESHOLD_OFFSET.

Also there are mechanisms in the algorithm to prevent the corruption of the calibration algorithm. As each sample makes its way into the algorithms, it enters a delay line. The sample length of the delay line is set by DELAY_LINE_NUMBER_OF_SAMPLES. Anything entering the delay line is shifted from one end to the other. If a value makes it through the delay line, it enters the algorithm computation and calibration is performed. The reason that a delay line is necessary is because if a user presents a card to a reader, there may be several detections before a read is performed. These detections, if not cleared, will cause the algorithm to adjust them out, eventually causing poor detection range. What happens in the current system is that once a read has been detected, this delay line is flushed by setting all values to the oldest value. It is expected that the time from the first detection to the read be no longer than DELAY_LINE_NUMBER_OF_SAMPLES / samples per second.

When a read has been detected, IGNORE_SAMPLES_AFTER_READ determines how many samples are thrown out afterwards. This prevents multiple reads or detections where the card is still in the field and thus corrupting the automatic calibration. It is expected that after IGNORE_SAMPLES_AFTER_READ samples, the user has removed the card from the reader detection range.

If these attempts to prevent erroneous samples from making it into the calibration algorithm do not work (for example, if the user has a hard time getting a read and keeps the card so long that the detections make their way through the delay line, or does a detection without a read) the algorithm is corrupted for a while. During that time, the detection and effectively read range are reduced. However, when the memory has been refreshed, after the erroneous value is aged out of the buffer, newer ones will come into effect, thus restoring the detection range once more.

The time for a complete memory refresh to happen is MOVING_WINDOW_WHERE_MAXIMUM_SAMPLE_IS_COMPENSATED_FOR / samples per second.

5.6 Testing the Device

To test a device, there is a rule that should be followed for normal operation. First, the automatic calibration will compensate out any noise that it sees. This also means card detections. When it does this, the detection range decreases. To prevent this loss of range on card detections, it is important to do a read within DELAY_LINE_NUMBER_OF_SAMPLES / samples per second seconds. When a read is performed, the samples in the delay buffer are set to its oldest value, thus preventing any corruption since they never get to the algorithm.

It should be noted that after a read, for IGNORE_SAMPLES_AFTER_READ / samples per second seconds there will be no possible detections or reads. This is necessary so that multiple reads are not performed and also allow the user to remove the card from the reader to prevent any more detections, which as mentioned before, would cause reduction of detection range.
5.7 Firmware Considerations

As can be seen in the detection and read range results in Figure 19, Figure 20, and Figure 21, there can be a significant difference in the detection and read range. An issue may occur where a card is detected, but the initial read cycle cannot read it because it has not reached the read range. This issue may be correct by increasing the THRESHOLD_OFFSET parameter. This will decrease detection range, bringing it closer to the read range – if so desired.

5.8 Comparator A+ Register Settings

This is the configuration that is used to measure the decay time of the output signal. These values are important to study if another type of comparator is needed to be used. Also for aid in interpreting these configurations, see Figure 8.

<table>
<thead>
<tr>
<th>Comparator A+ Register</th>
<th>Value</th>
<th>Description</th>
</tr>
</thead>
<tbody>
<tr>
<td>CACTL1</td>
<td></td>
<td></td>
</tr>
<tr>
<td>CAEX</td>
<td>0</td>
<td>No invert</td>
</tr>
<tr>
<td>CARSEL</td>
<td>0</td>
<td>V_CAREF is applied to the + terminal</td>
</tr>
<tr>
<td>CAREF</td>
<td>2</td>
<td>Voltage reference set to 0.5VCC</td>
</tr>
<tr>
<td>CAON</td>
<td>1</td>
<td>Comparator enabled at sampling period</td>
</tr>
<tr>
<td>CAIES</td>
<td>0</td>
<td>Rising edge interrupt</td>
</tr>
<tr>
<td>CAIE</td>
<td>1</td>
<td>Comparator interrupt is enabled for sampling</td>
</tr>
<tr>
<td>CAIFG</td>
<td>X</td>
<td>Indicates that a comparator interrupt has occurred</td>
</tr>
<tr>
<td>CACTL2</td>
<td></td>
<td></td>
</tr>
<tr>
<td>CASHORT</td>
<td>0</td>
<td>Inputs are not shorted</td>
</tr>
<tr>
<td>P2CA4</td>
<td>0</td>
<td>Positive input is routed to high-impedance input pin</td>
</tr>
<tr>
<td>P2CA3</td>
<td>0</td>
<td>Negative input is routed to CA1 input pin</td>
</tr>
<tr>
<td>P2CA2</td>
<td>0</td>
<td>See above</td>
</tr>
<tr>
<td>P2CA1</td>
<td>1</td>
<td>See above</td>
</tr>
<tr>
<td>P2CA0</td>
<td>0</td>
<td>See above</td>
</tr>
<tr>
<td>CAF</td>
<td>1</td>
<td>Comparator output is filtered</td>
</tr>
<tr>
<td>CAPD</td>
<td></td>
<td></td>
</tr>
<tr>
<td>CAPD1</td>
<td>1</td>
<td>Pin CA1 input buffer is disabled</td>
</tr>
<tr>
<td>CAPDX</td>
<td>0</td>
<td>The rest of the input buffers are not disabled</td>
</tr>
</tbody>
</table>

6 Measured Current Consumption

Figure 18 shows a breakdown of current consumption during each stage or step during the card presence detection monitor process for running the process three times in one second. This is where the three times a second interval (approximately 336 ms) is coming from, and if it needs to be sped up or slowed down, this is simple change to make. Also, in the case of building access systems that are "learning" the occupant's behaviors and adjusting energy consumption accordingly, this would be the variable that the firmware algorithm would be changing.
The first spike of the current graph is where the bypass capacitors are being instantaneously charged. Immediately afterwards is the TRF79xxA initialization and then the sleep period. The last spike is for the actual RF carrier transmitter burst and the sampling period afterwards.

Table 2. Current Consumption\(^{(1)}\)

<table>
<thead>
<tr>
<th>Cycle Name</th>
<th>Time</th>
<th>Average Current</th>
<th>Description Of Process</th>
</tr>
</thead>
<tbody>
<tr>
<td>Main Sleep Cycle</td>
<td>333 ms</td>
<td>0.8 µA</td>
<td>Time determines polling frequency</td>
</tr>
<tr>
<td>A TRF79xxA Enable</td>
<td>56 µs</td>
<td>27.4 mA</td>
<td>TRF79xxA is enabled</td>
</tr>
<tr>
<td>B Configure TRF79xxA</td>
<td>88 µs</td>
<td>8.45 mA</td>
<td>SPI communication</td>
</tr>
<tr>
<td>C Initialization Sleep Cycle</td>
<td>2.736 ms</td>
<td>1.45 mA</td>
<td>Sleep cycle for crystal to turn on</td>
</tr>
<tr>
<td>D Next Init, Clock Switch</td>
<td>232 µs</td>
<td>2.28 mA</td>
<td>MCU starts to be sourced by TRF79xxA’s clock</td>
</tr>
<tr>
<td>E Sampling Cycle</td>
<td>304 µs</td>
<td>6.01 mA</td>
<td>Transmitter burst and sampling</td>
</tr>
<tr>
<td></td>
<td>488 µs</td>
<td></td>
<td></td>
</tr>
<tr>
<td>Total Period</td>
<td>336.4 ms</td>
<td></td>
<td></td>
</tr>
</tbody>
</table>

\(^{(1)}\) Assumption: VCC = 3.0V, Polling: three times per second
\(^{(2)}\) 304 µs is the time until de-assertion of EN signal. 488 µs is the time until current from active cycle returns to normal (using 304 µs).
7 Card Detection and Activation Results

The solution presented was tested with ISO15693, ISO14443A, and ISO14443B tags and cards of various common form factors. The TRF7970AEVM was used with 3VDC supply and its on-board antenna. The detection and read range results can be seen in Figure 19, Figure 20, and Figure 21.

### Table 3. Average Current per Polling Frequency

<table>
<thead>
<tr>
<th>Polling Frequency (per second)</th>
<th>Average Current</th>
</tr>
</thead>
<tbody>
<tr>
<td>1 Hz</td>
<td>12 µA</td>
</tr>
<tr>
<td>2 Hz</td>
<td>21 µA</td>
</tr>
<tr>
<td>(example provided) 3 Hz</td>
<td>31 µA</td>
</tr>
<tr>
<td>4 Hz</td>
<td>41 µA</td>
</tr>
<tr>
<td>5 Hz</td>
<td>51 µA</td>
</tr>
</tbody>
</table>

![ISO15693 Transponder Detection Ranges and UID Read Ranges](image_url)
Regarding low read ranges seen in this figure, the 32mm x 32mm inlay is a Mifare Ultra Light C device with a measured low Q, 34mm circular inlay was made from NTAG203 with a measured resonant frequency of 14.62MHz, 45mm x 76mm tag is a DESFire EV1 inlay with a measured resonant frequency of 15.275MHz. These are devices purchased or obtained through public distribution channels and could have been designed and/or manufactured with higher quality control. The point here is that most likely the poor read range is not the fault of the IC maker, but the inlay manufacturer. In Figure 19, the TI inlay quality is high and controlled and, thus, the detection and read ranges track each other in a more linear fashion.

Figure 20. ISO14443A Detection and Read Ranges

Assumptions for these range tests: THRESHOLD_OFFSET was set to 4. USE_AUTOMATIC_CALIBRATION was not defined. Device was being reset periodically to run through the initial calibration.

Figure 21. ISO14443B Detection and Read Ranges
8 Summary

It is critical to realize that average current consumption goes down as the wait times in between the
detection cycles are made longer. Most competitive parts that might be claiming to have card detection
built in are most likely putting out a voltage on their antenna coil (like we are), but then they are using a
DAC to measure current changes. Here we are putting out a voltage and measuring a change in that
voltage directly using the Comparator_A+ and timer hardware that is already built in to the MSP430 MCU.
Using this approach, we can achieve lower power consumption by comparison and only get better as time
in between "sniff" cycles is increased.

Using a standard TRF79xxA EVM and adding few passive components, a highly power efficient system
may be realized. This system may allow its use in battery powered applications with very little added extra
cost.

Along with an automatic calibrating algorithm, voltage or temperature drifts do not cause unnecessary
false positives and thus conserve power.

For developers of NFC/RFID systems that operate from battery power or need to conserve energy as
much as possible as part of their value proposition to the end customer/consumer, the superior card
presence detection solution outlined in this document, using the TRF79xxA and an MSP430 in conjunction
with the firmware approach, is the path to achieving the ultra low power operations in their application.

9 References

- TRF7970A Data Sheet (SLOS743)
- MSP430F23x0 Data Sheet (SLAS518)
- MSP430G2xx Family (MSP430G2xx Family)
- MSP430x2xx Family User's Guide (SLAU144)
- Economic Measurement Techniques With the Comparator_A Module (SLAA071)
- ISO/IEC15693-2 (ISO/IEC15693-2)
- ISO/IEC15693-3 (ISO/IEC15693-3)
Appendix A TRF7970AEVM Schematic Modifications

Figure 22. Schematic

These changes are necessary to convert an TRF7970AEVM to a card reader per App Note

Note: Set for SPI mode.

Note: Connected to 10 degrees BNC.
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